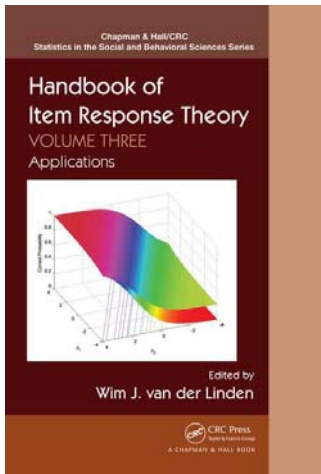


社会・行動科学におけるチャップマン&ホール/ CRC の統計シリーズ



項目反応理論ハンドブック 第3巻

Handbook of Item Response Theory, Vol.3 : Applications

By Wim J. van der Linden

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持長

全3巻の第3巻で教育や心理学的測定、患者報告アウトカムの医学的診断、およびマーケティングリサーチにおける試験の毎日の練習に項目反応理論(IRT)のアプリケーションの主要な領域はカバーしています。

Drawing on the work of internationally acclaimed experts in the field, Handbook of Item Response Theory, Volume Three: Applications presents the major areas of applications of item response theory (IRT) to the daily practice of testing in educational and psychological measurement, medical diagnosis of patient-reported outcomes, and marketing research.

This third volume in a three-volume set highlights the contributions IRT has made to test theory, including item calibration and analysis, person fit and scoring, and test design. It explores how IRT has advanced areas, such as large-scale educational assessments, psychological testing, cognitive diagnosis, health measurement, marketing research, and the more general area of measurement of change. Volume Three also covers CRAN packages, WinBUGS, Bilog MG, Multilog, Parscale, IRTPRO, Mplus, GLLAMM, Latent Gold, and numerous other software tools.

目次

I: Item Calibration and Analysis

Item-Calibration Designs

Martijn P.F. Berger

Parameter Linking

Wim J. van der Linden and Michelle D. Barrett

Dimensionality Analysis

Robert D. Gibbons and Li Cai

Differential Item Functioning *Dani Gamerman, Flávio B. Goncalves, and Tufi M. Soares*

Calibrating Technology-Enhanced Items

Richard M. Luecht

II: Person Fit and Scoring

Person Fit

Cees A. W. Glas and Naveed Khalid

Score Reporting and Interpretation

Ronald K. Hambleton and April L. Zenisky

IRT Observed-Score Equating

Wim J. van der Linden

III: Test Design

Optimal Test Design

Wim J. van der Linden

Adaptive Testing

Wim J. van der Linden

Standard Setting

Daniel Lewis and Jennifer Lord-Bessen

**Test Speededness and Time Limits
Item and Test Security**

*Wim J. van der Linden
Wim J. van der Linden*

IV: Areas of Application

Large-Scale Group-Score Assessments
Psychological Testing
Cognitive Diagnostic Assessment
Health Measurement
Marketing Research
Measuring Change Using Rasch Models

*John Mazzeo
Paul De Boeck
Chung Wang and Hua-Hua Chang
Richard C. Gershon, Ron D. Hays, and Michael Kallen
Martijn G. de Jong and Ulf Böckenholt
Gerhard H. Fischer*

V: Computer Programs

IRT Packages in R
Bayesian Inference Using Gibbs Sampling (BUGS) for IRT Models
BILOG-MG
PARSCALE
IRTPRO
Xcalibre 4
EQSIRT
ACER ConQuest
Mplus
GLLAMM
Latent GOLD
WinGen
Firestar
jMetrik

*Thomas Rusch, Patrick Mair, and Reinhold Hatzinger
Matthew S. Johnson
Michele F. Zimowski
Eiji Muraki
Li Cai
Nathan A. Thompson and Jieun Lee
Peter M. Bentler, Eric Wu, and Patrick Mair
Raymond J. Adam, Margaret L. Wu, and Mark R. Wilson
Bengt Muthén and Linda Muthén
Sophia Rabe-Hesketh and Anders Skrondal
Jeroen K. Vermunt
Kyung (Chris) T. Han
Seung W. Choi
J. Patrick Meyer*

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